Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/590,839	CHYUN, CHAN HYUK
Examiner	Art Unit
Hongmin Fan	2612

SEARCHED				
Class	Subclass	Date	Examiner	
340	541	1/28/2008	HF	
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	565-567			
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INTERFERENCE SEARCHED			
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	 DATE	EXMR
B. Lee D. Goins	1/28/2008	HF
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